



5/9/2009

**RELIABILITY MONITOR REPORT
FOR**

MFN SiGe HBT

MAXIM Integrated Products

**120 San Gabriel Dr.
Sunnyvale, CA 94086**

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3660ETE+

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 5730 FITS: 19.9

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 1/1/2008 and 12/31/2008.

Process Information:

Process Description: MFN SiGe HBT

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0746	MAX3660ETE+	135C	428 HRS	48	0	NEWZAU002D
HIGH TEMP OP LIFE	0826	MAX3660ETE+	135C	192 HRS	48	0	NEWZD3007AQ
				Total:		0	

FAILURE RATE: MTTF (YRS): 5730 FITS: 19.9